

# Vertex Detector at CLIC

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# Outline

- Requirements
- Simulation layouts
- Performance optimisation
- Integration, assembly and cooling
- Sensor- and readout-technology R&D

Occupancies and radiation exposure:

→ André Sailer's presentation on backgrounds

# Requirements

- Integral part of **tracking** systems (in particular for low  $p_T$ )
- Efficient **tagging of heavy quarks + tau leptons** through precise determination of displaced vertices:

$$\sigma(d_0) = \sqrt{a^2 + b^2 \cdot \text{GeV}^2 / (p^2 \sin^3 \theta)}$$

$$a \approx 5\mu\text{m} \quad b \approx 15\mu\text{m}$$

- **Good single point resolution**:  $\sigma_{\text{SP}} \sim 3 \mu\text{m}$
- **Low material budget**:  $X \approx 0.2\% X_0$  / layer (incl. cooling)
- **Full coverage** down to low polar angles  $\theta_{\text{min}} \sim 7^\circ$
- **Few % occupancy** despite large background rates
- **Time stamping** with 5-10 ns accuracy, to reject background
- To date: no technology option available fulfilling all requirements
- **Simulation studies**: impact of layout on performance
- **Integration/Assembly + cooling**
- Discuss ongoing and future **R&D on sensors & readout**

# Simulation layout CLIC\_ILD

Fig. 4.1a

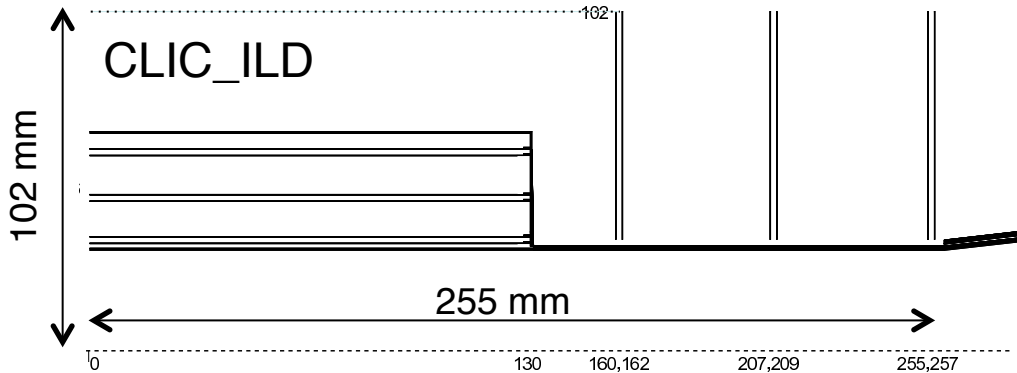
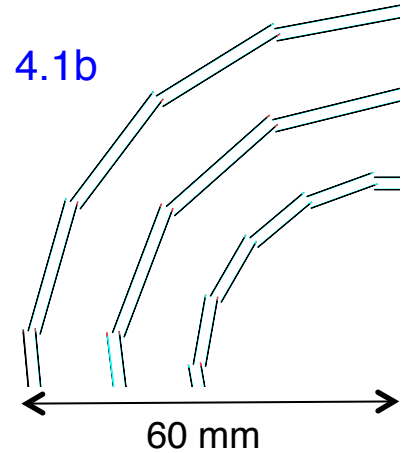


Fig. 4.1b



Tab. 4.1

	CLIC_ILD	CLIC_SiD
Central beam pipe	Beryllium	Beryllium
	$R_i = 29.4$ mm $d = 0.6$ mm	$R_i = 24.5$ mm $d = 0.5$ mm
Barrel region	3 double layers $ z  < 130$ mm $R_i = 31, 44, 58$ mm	5 single layers $ z  < 98.5$ mm $R_i = 27, 38, 51, 64, 77$ mm
Forward region	3 double layers $z = 160, 207, 255$ mm	7 single layers $z = 120, 160, 200, 240, 280, 500, 830$ mm
Sensors	$20 \mu\text{m} \times 20 \mu\text{m}$ , $\sigma_{sp} \approx 3 \mu\text{m}$ $X/X_0 = 0.18\%$ per double layer	$X/X_0 = 0.11\%$ per single layer
Surface area	$0.736 \text{ m}^2$	$1.103 \text{ m}^2$
Number of channels	$1.84 \times 10^9$	$2.76 \times 10^9$

# Simulation layout CLIC\_SiD

Fig. 4.2a

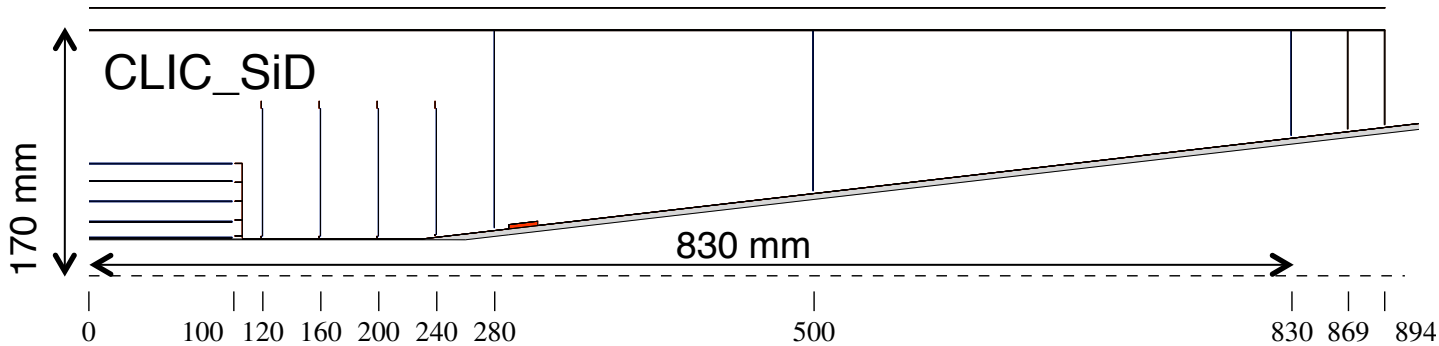
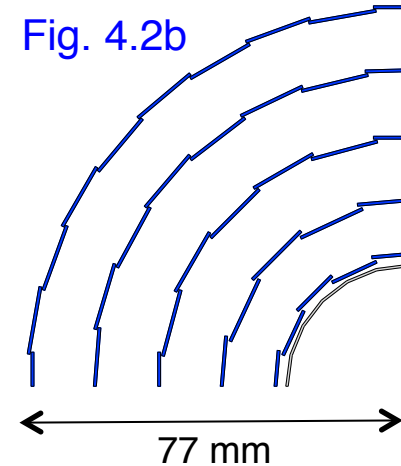


Fig. 4.2b



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# Material budget vertex region

Fig. 4.3a

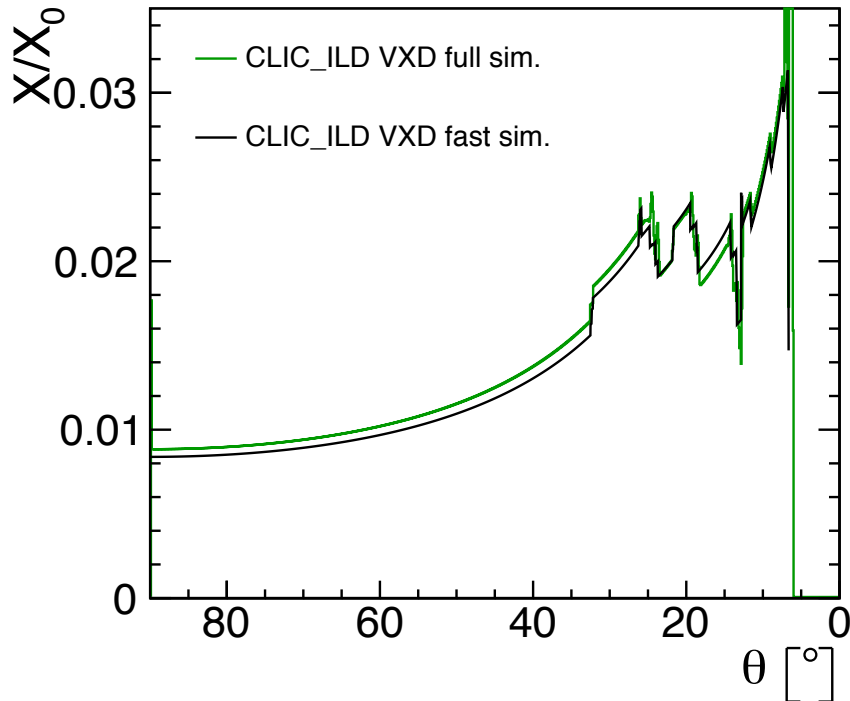
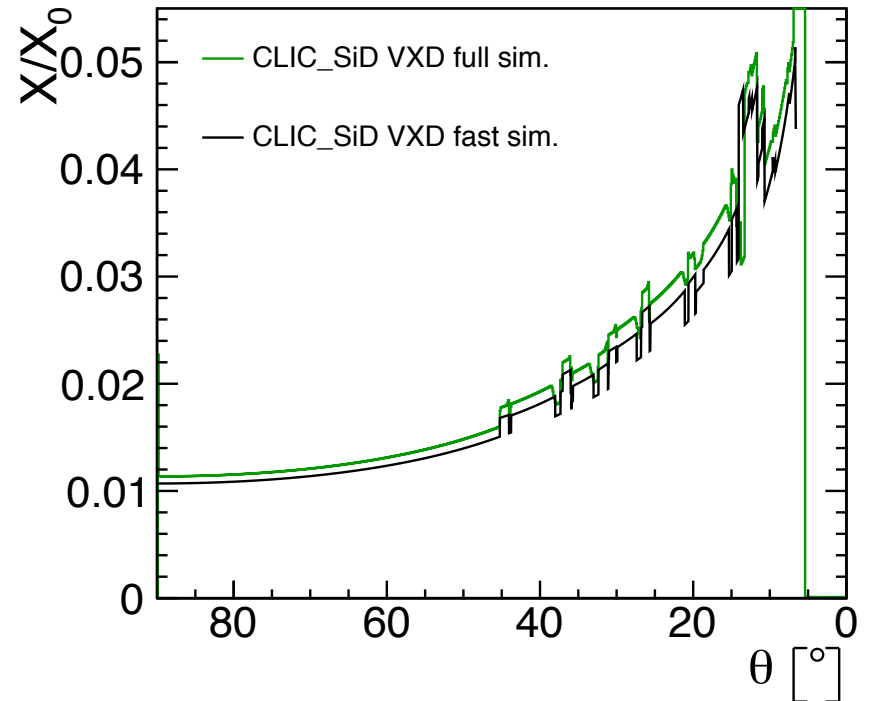


Fig. 4.3b



- Integrated amount of material seen by particles originating from the IP:  
 $X/X_0 \sim 1\%$  (at  $\theta=90^\circ$ , averaged over  $\phi$ )
- Good agreement full / fast simulation  
(fast simulation has only ideal cylinders and disks, no module overlaps)

# Transverse impact-parameter resolution

$d_0$ : distance of closest approach to interaction point in R-phi plane  
→ main benchmark parameter for vertex detector performance

**Fast simulation:** LiC detector toy tool, used for design optimisation

**Full simulation:** Geant4-based ILD/SiD frameworks, used for physics studies

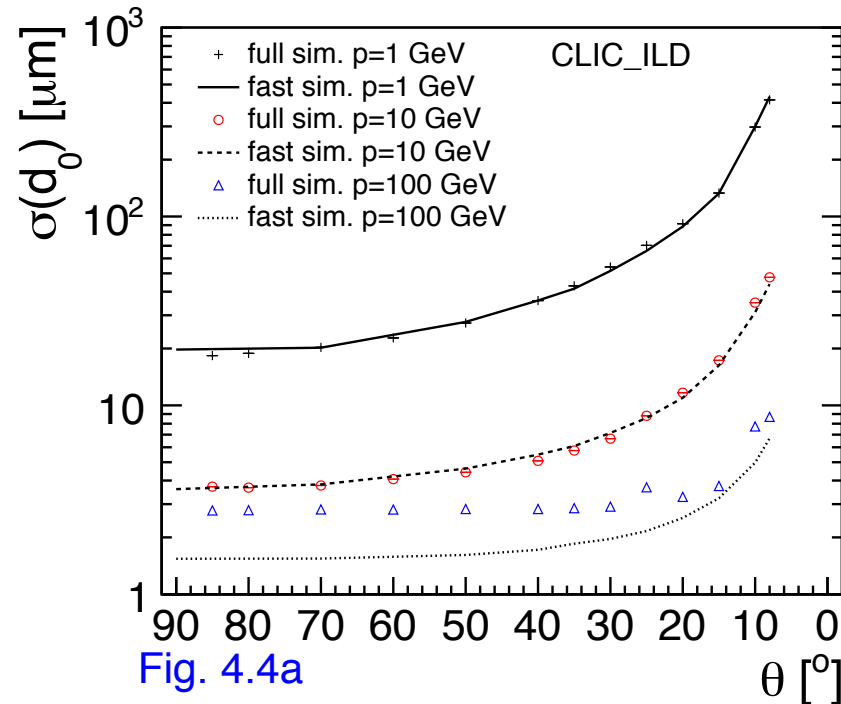


Fig. 4.4a

## CLIC\_ILD:

- Both full and fast simulation perform simple Gaussian hit smearing
- Full simulation without TPC information  
→ Worse resolution for high momenta

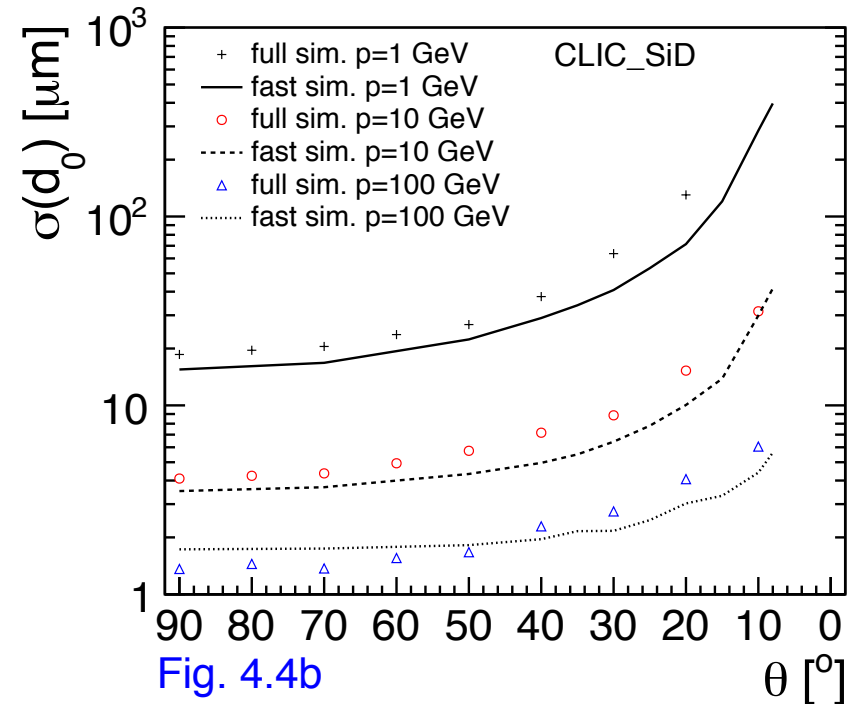


Fig. 4.4b

## CLIC\_SiD:

- Full simulation models clustering according to parametrisation of KPiX readout chip  
→ added realism leads to worse resolution in full simulation, as expected

# Dependence on single-point resolution

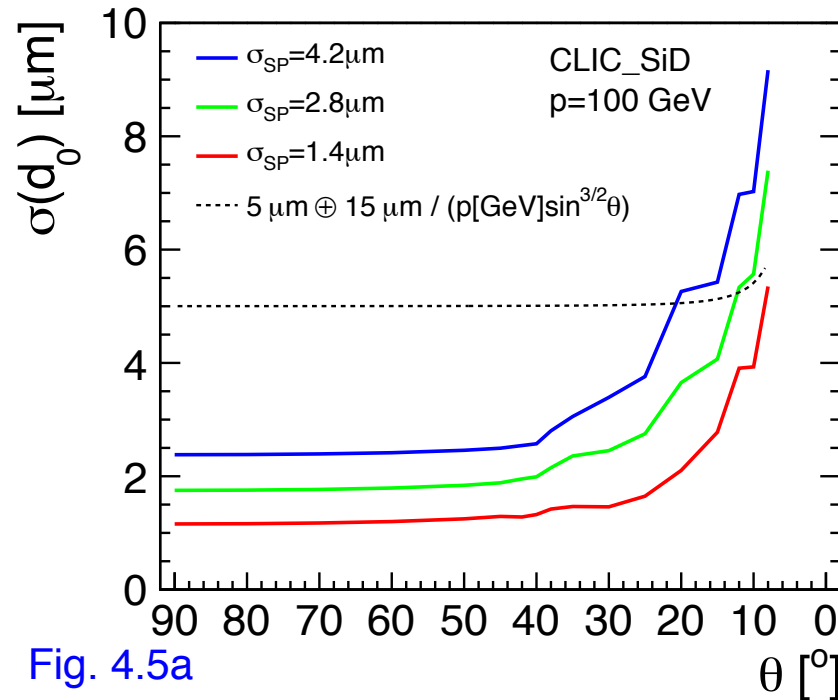


Fig. 4.5a

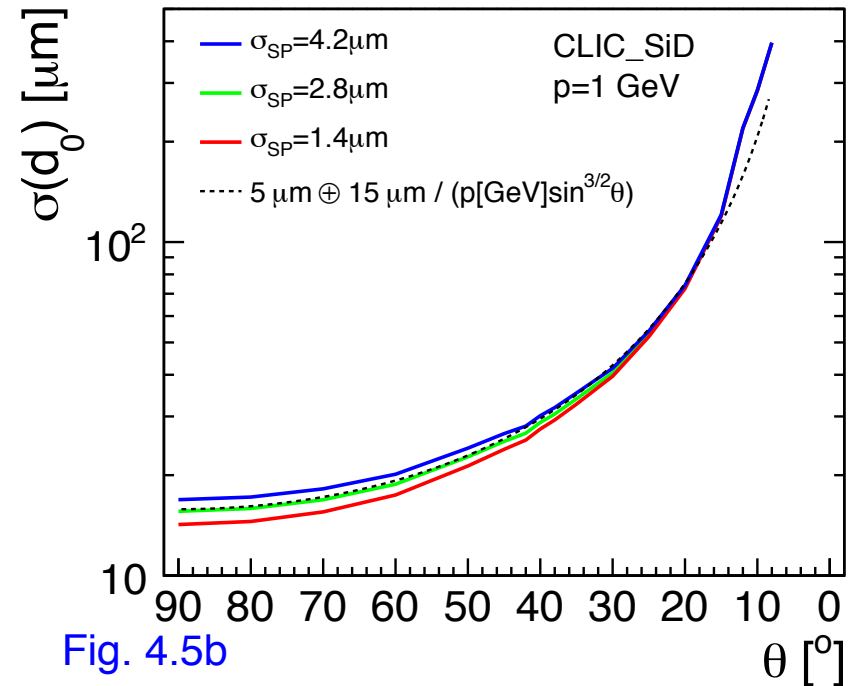


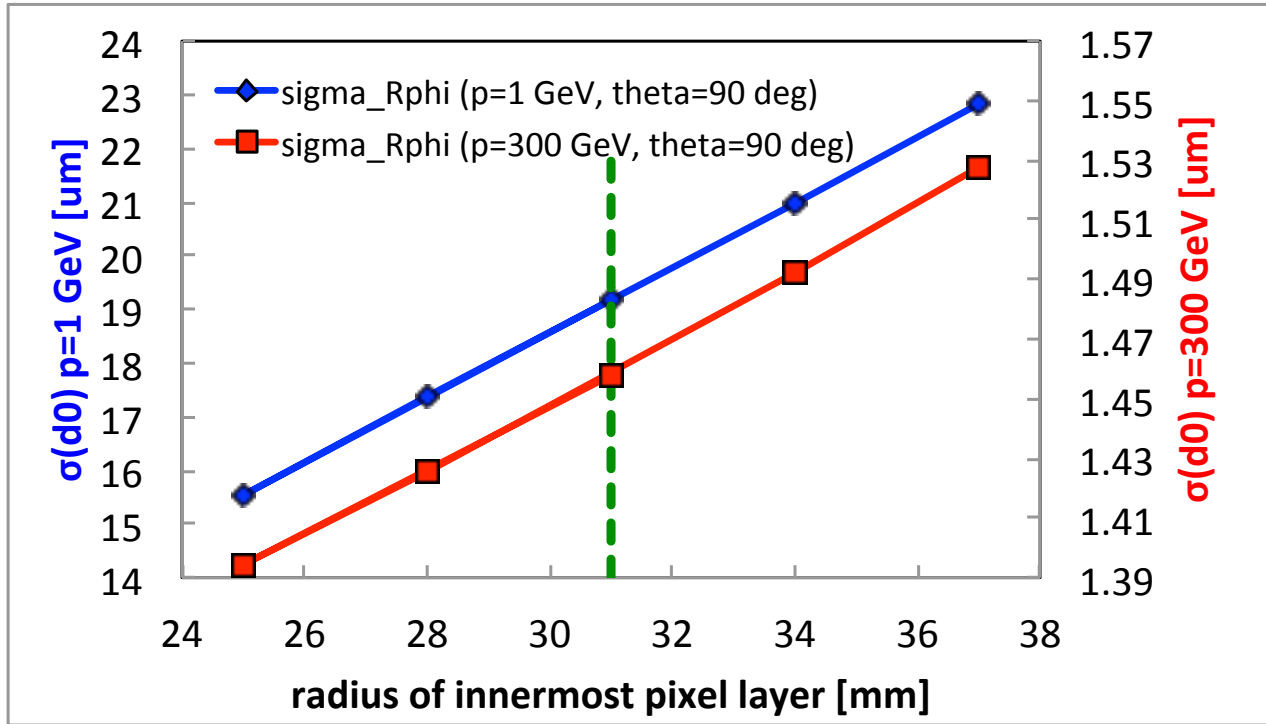
Fig. 4.5b

- Varied **single-point resolution** by  $\pm 50\%$  ( $\sim$  pixel sizes 10x10, 20x20, 30x30  $\mu\text{m}^2$ )
- Observed change in  $d_0$ -resolution:
  - $\pm 40\%$  for  $p = 100$  GeV
  - $\pm 15\%$  for  $p = 1$  GeV
- Resolution close to or better than target values for all cases
- Pixel size is also constrained by:
  - Expected background occupancy
  - Ability to separate adjacent tracks in dense jets



# Dependence on distance to IP

Fig. 4.6



- Varied **distance to interaction point**, by changing radii of beam pipe and barrel vertex layers in CLIC\_ILD model
- Observed change in d<sub>0</sub>-resolution:
  - 3.2% / mm for high momenta (parameter 'a')
  - 0.8% / mm for low momenta (parameter 'b')
- Distance to interaction point is constrained by direct hits from incoherent pairs (see André Sailer's presentation on backgrounds)

# Dependence on material

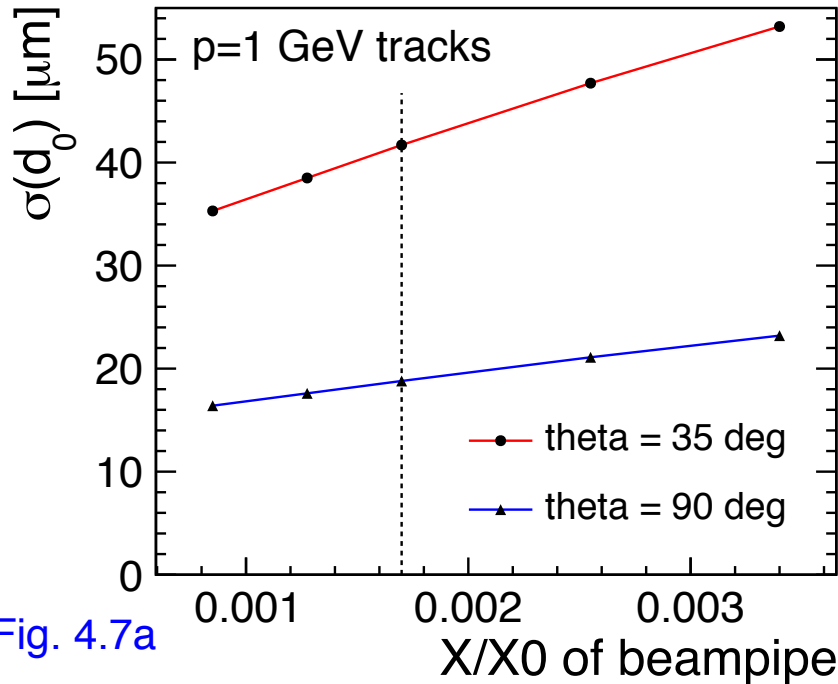


Fig. 4.7a

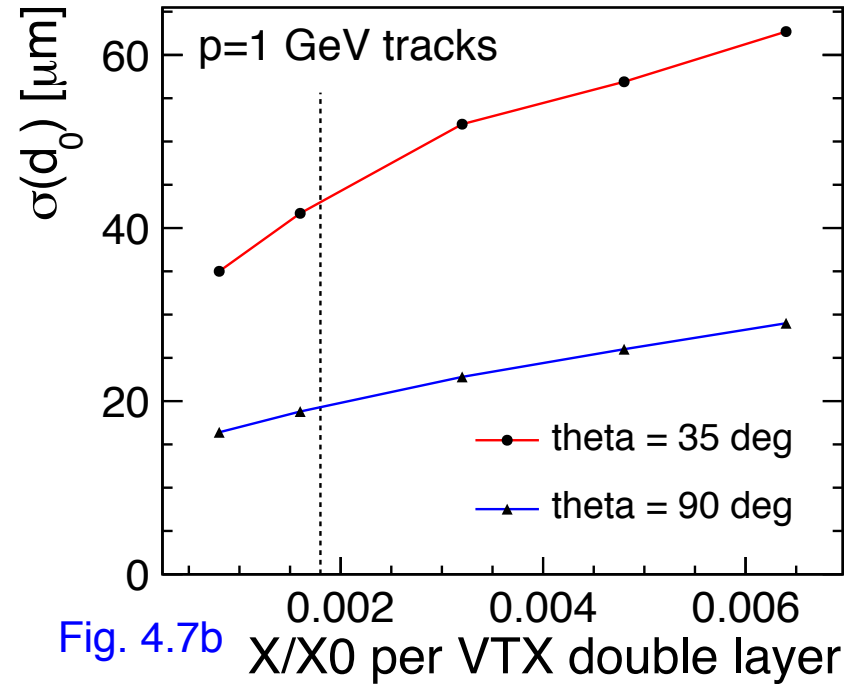


Fig. 4.7b

- Very small amount of material in baseline designs
- Realistic models for supports, cabling, cooling not available yet
- Studied sensitivity of  $d_0$  resolution for low momenta on material in beampipe and silicon pixel layers of CLIC\_ILD
- Doubling beam-pipe thickness  $\rightarrow$   $\sim 20\%$  worse resolution at  $90^\circ$
- Doubling material in silicon layers  $\rightarrow$   $\sim 20\%$  worse resolution at  $90^\circ$
- Steeper slope in forward region

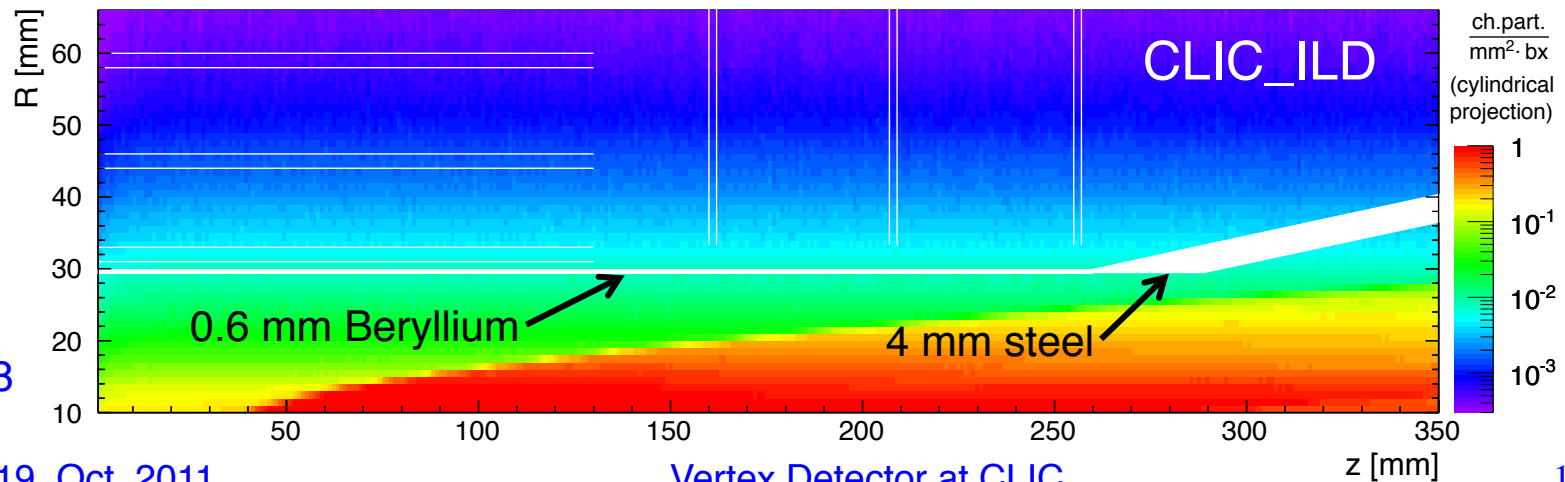
# Beam pipe

Requirements for beam pipe:

- Provide good vacuum  $\rightarrow$  leak tightness
- Minimise multiple scattering  $\rightarrow$  small amount of material in central part
- Allow for placement of Si layers close to IP  $\rightarrow$  small radius
- Stay outside region of high background occupancy  $\rightarrow$  lower limit on radius
- Shield against back scatters from forward region  $\rightarrow$  thick conical part outside VTX acceptance

Implementation in simulations:

- Central Beryllium part:
  - CLIC\_ILD:  $d=0.6$  mm,  $R=29.4$  mm ( $B=4$  T)
  - CLIC\_SiD:  $d=0.5$  mm,  $R=24.5$  mm ( $B=5$  T)
  - Safe w.r.t. backgrounds, vacuum collapse, leak tightness (D0, CDF experience in run II)
  - Unlike ILC: no extra shielding, due to low expected levels of incoh. synchrotron radiation (t.b.c.)
- Forward conical part:
  - 4 mm iron, to shield against back scatters from forward region
  - Pointing to interaction point  $\rightarrow$  no extra material inside tracking acceptance



# Assembly and Integration (CLIC\_SiD)

Fig. 4.10

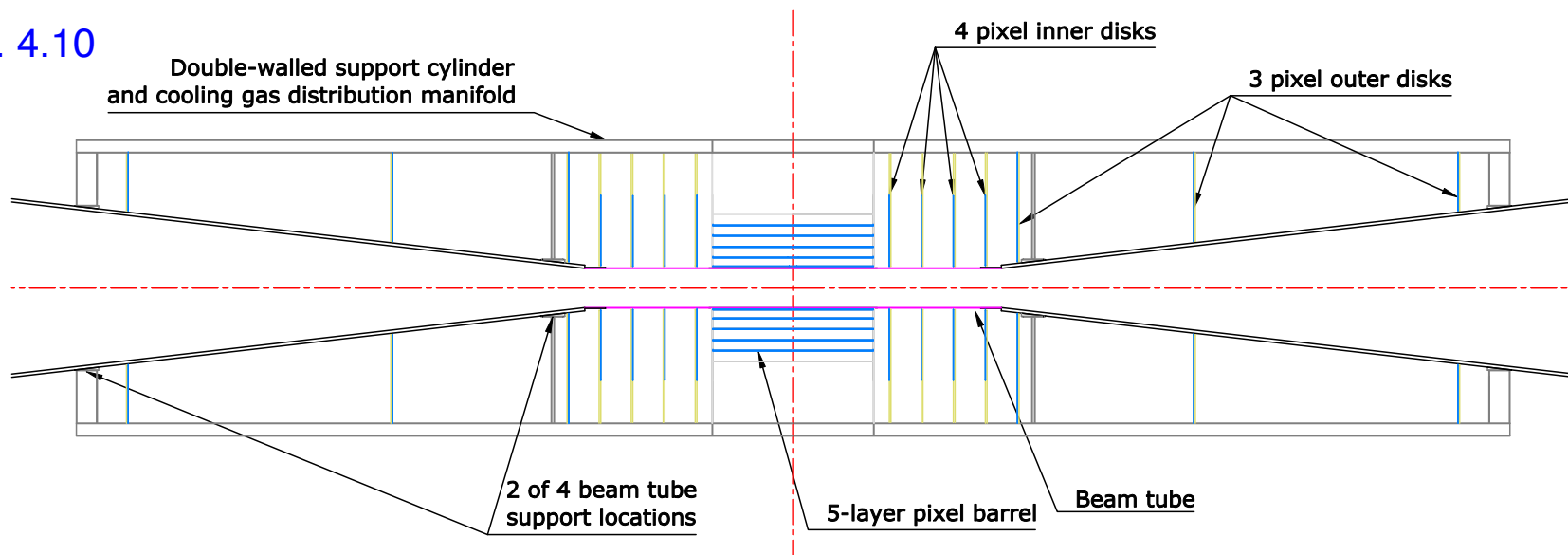
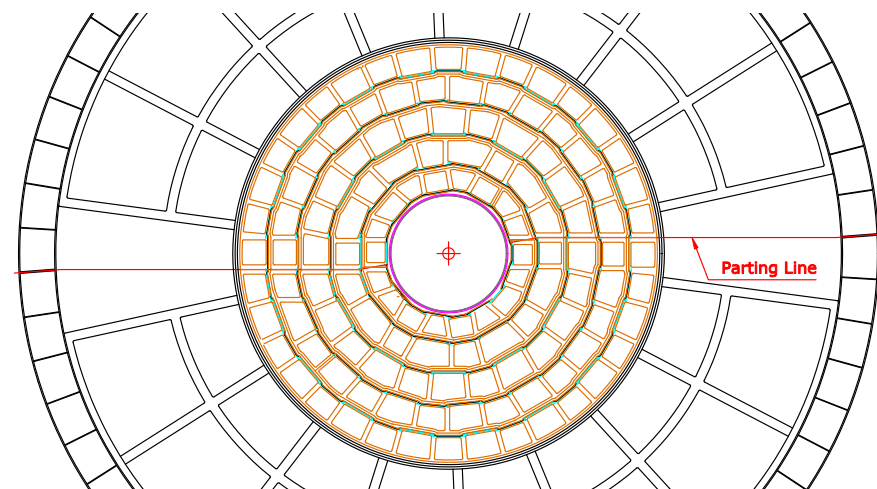


Fig. 4.11



- Assembly in two halves  
→ separation from beam pipe assembly
- Double-walled carbon fibre outer support cylinder + support disks
  - supported by conical part of beam pipe
  - Keep central part of beam pipe straight
- Longitudinal passages for cooling gas
- Sensor assembly to be defined:
  - glued to each other or glued to CF support
  - CF end rings to control roundness
  - Spoked CF membranes to connect layers

# Cooling

- $P \sim 500 \text{ W}$  in vertex detectors ( $50 \text{ mW/cm}^2$ )
- Need efficient cooling, meeting material budget requirements

## Forced (dry) air flow

- baseline for barrel region
- no extra material
- CLIC\_SiD calculation:  
 $T_{\text{in}} = 16^\circ\text{C}$ ,  $T_{\text{ladders}} \sim 25^\circ\text{C}$   
→ up to **240 liter/s** flow,  
**~40 km/h** flow velocity
- Innermost layer critical
- Possible improvements:  
lower  $T_{\text{in}}$  and/or allow for higher  $T_{\text{ladders}}$

## Evaporative $\text{CO}_2$ cooling

- Option for supplementary cooling in forward disks
- High pressure up to  $\sim 70 \text{ bar}$ , requires rather thick tubing
- $\sim 2.7\%$   $X_0$  per tube (incl. coolant)

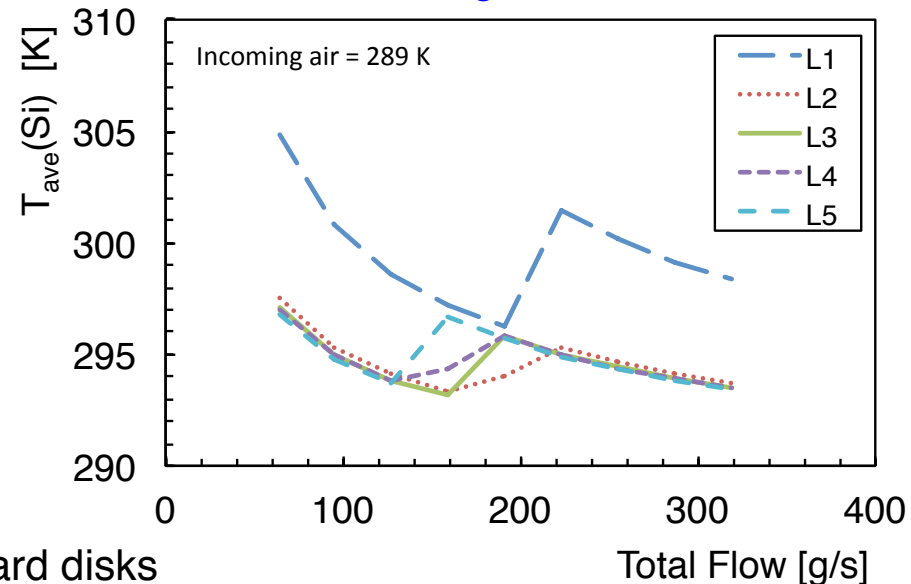
## Water cooling

- Option for supplementary cooling in forward disks
- Sub-atmospheric pressure
- Can use thin PEEK pipes → lower material budget than  $\text{CO}_2$ ,  $\sim 0.4\%$   $X_0$  per tube

## Micro-channel cooling

- Ongoing R&D (e.g. NA62 Gigatracker upgrade)
- Integrate cooling channels in Silicon
- Connectors pose major challenge

Fig. 4.12



# Pixel-detector technology options

- 20x20  $\mu\text{m}^2$  pixel sizes  $\rightarrow$  need small feature sizes
- Time-stamping  $\sim 5\text{-}10$  ns  $\rightarrow$  need high-resistivity sensor
- $\sim 0.2\%$  material/layer  $\rightarrow$  corresponds to  $\sim 200$   $\mu\text{m}$  silicon (incl. support + cables)
- 156 ns bunch train every 20 ms  $\rightarrow$  trigger-less readout, power pulsing
- Radiation exposure  $< 10^{11}$   $n_{\text{eq}}/\text{cm}^2/\text{yr}$   $\rightarrow$  radiation hardness not a major concern

## Possible technology development paths:

### 1) Hybrid or multi-tier technologies

- Thinned high-resistivity fully depleted sensors
- Fast, low-power highly integrated readout chip
- Low mass interconnects
- Pros: factorisation of sensor + readout R&D; r/o chips profit fully from advancing industry standards
- Cons: interconnect difficult/expensive; harder to reduce material

### 2) Integrated technologies

- Sensor and readout combined in one chip or 3D integration of multiple tiers
- Charge collection in epitaxial layer (typically  $< 1$   $\mu\text{m}$ )
- Pros: allows for very low material solutions; synergy with R&D for ILC detectors
- Cons: harder to achieve good time resolution and sufficient S/N

# Examples for Hybrid Approach

- Thinned high-resistivity fully depleted sensors
  - ALICE pixel upgrade: 50  $\mu\text{m}$  silicon sensors (IZM)
  - Handling is a concern, in particular for larger structures
- Fast, low-power readout ASICs in Very-Deep-Sub-Micron (VDSM) technology
  - Timepix3: 55  $\mu\text{m}^2$ , 130 nm
    - CLICPix (prototypes ~2014): 20  $\mu\text{m}^2$ , 65 nm
  - ALICE1LHCb r/o chip: 50x425  $\mu\text{m}^2$ , 250 nm
    - upgrade (prototypes ~2012-13): 30x30  $\mu\text{m}^2$ , 130-180 nm
- Low-mass interconnects and pixel connectivity
  - Through Silicon Vias (TSV):
    - fan out ASIC contacts to backside through vertical conducting channel
    - avoids dead areas from wire-bonding pads around the chips
    - Implem. example: CEA-Leti (Medipix3, prototypes 2011-12)
  - 3D interconnects
    - Interconnection of separately optimised tiers in different technologies
  - Lateral interconnectivity
    - Edgeless sensors
    - Stitching of CMOS arrays

# Examples for Integrated Approach

- Active R&D programs for integrated technologies, targeted to ILC requirements
- Attempts to reach faster signal collection and  $\sim$ ns time-stamping capability, compatible with CLIC requirements:
  - MIMOSA CMOS chip family (currently 350 nm) in STAR, EUDET Telescope
    - developing high-resistivity epitaxial layers, smaller feature sizes
  - Chronopixel CMOS sensors with fully depleted epitaxial layer
  - INMAPS technology: deep p-well barrier protects n-well charge collector, improves charge collection, allows for high-resistivity epitaxial layer and full-featured CMOS MAPS technology
  - High-voltage CMOS: CMOS signal processing electronics embedded in reverse-biased deep n-well that acts as signal collecting electrode
  - Silicon-On-Insulator (SOI):  $\sim$ 200 nm  $\text{SiO}_2$  isolation layer separates charge collection and readout functionality
  - Full 3D-integrated pixel solutions: Thinned high-resistivity sensitive tier coupled to additional tiers with advanced analog+digital functionality
- Concerns for CLIC:
  - Long-term availability of processes
  - Suitability for large-scale systems
  - prefer staged developments and synergy with industrial trends



# Future Work

- Simulation, Layout + Integration:
  - Improve realism of simulation for digitization / reconstruction (signal development, clustering, charge sharing, resolution, angular dependence, single-event effects, etc.)
  - Improve models for cabling / supports / cooling
  - Develop low-mass support structures
  - Work out assembly, integration and access scenarios
  - Strengthen link to physics requirements: heavy flavour tagging, benchmark studies involving forward physics
  - Re-optimize geometry in view of all of the above
- Sensor + Readout R&D:
  - Develop pixel detector with small pitch ( $\sim 20 \mu\text{m}$ ) and fast time stamping of hits ( $\sim 5 \text{ ns}$ )
    - Hybrid or multi-tier
    - Integrated CMOS technologies
  - Low-mass interconnects for vertical and lateral integration
  - Thinning of wafers to  $\sim 50 \mu\text{m}$
  - Power delivery and power reduction techniques ( $P \lesssim 50 \text{ mW} / \text{cm}^2$ )
    - Power-pulsing + air cooling in magnetic field

# Summary / Conclusions

- CLIC environment + physics requirements pose challenging demands on vertex-detector systems
- Presented initial layout proposals meeting those demands
- Studied dependence of performance on layout parameters
- Integration, Assembly and Cooling considerations
- Examples for active R&D on sensor + readout technologies, aiming to meet the CLIC requirements